

<b>Notice of References Cited</b>	Application/Control No. 10/631,928		Applicant(s)/Patent Under Reexamination TEOH ET AL.	
	Examiner Victor X. Nguyen		Art Unit 3734	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,128,073	10-2006	van der Burg et al.	128/887
*	B	US-6,454,780	09-2002	Wallace, Michael P.	606/151
*	C	US-6,344,048	02-2002	Chin et al.	606/200
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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